

RoHS Compliant Product  
A suffix of "-C" specifies halogen and lead-free

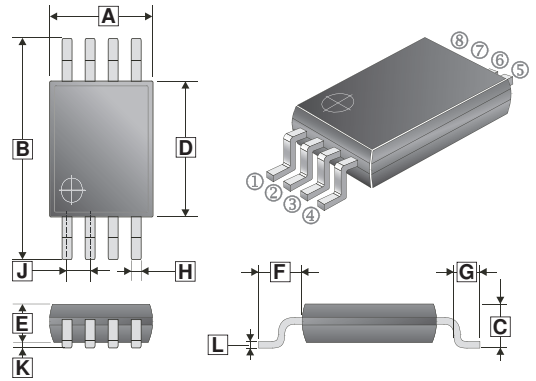
## DESCRIPTION

These miniature surface mount MOSFETs utilize a High Cell Density trench process to provide Low  $R_{DS(on)}$  and ensure minimal power loss and heat dissipation. Typical applications are DC-DC converters and power management in portable and battery-powered products such as computers, printer, PCMCIA cards, cellular and cordless telephones.

## FEATURES

- Low  $R_{DS(on)}$  provides higher efficiency and extends battery life.
- Low thermal impedance copper leadframe TSSOP-8 saves board space.
- Fast switching speed.
- High performance trench technology.

## TSSOP-8

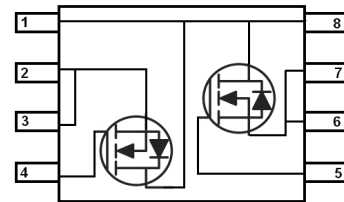


REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	2.80	3.10	G	0.45	0.75
B	6.20	6.60	H	0.19	0.30
C	1.00	1.20	J	0.65	REF.
D	4.30	4.50	K	0.05	0.15
E	-	1.15	L	0.127	REF.
F	0.9	1.10			

## PACKAGE INFORMATION

Package	MPQ	Leader Size
TSSOP-8L	3K	13' inch

## Top View



## ABSOLUTE MAXIMUM RATINGS ( $T_A=25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	$V_{DS}$	20	V
Gate-Source Voltage	$V_{GS}$	$\pm 8$	V
Continuous Drain Current <sup>1</sup>	$I_D$	$T_A=25^\circ\text{C}$	6.8
		$T_A=70^\circ\text{C}$	5.4
Pulsed Drain Current <sup>2</sup>	$I_{DM}$	30	A
Continuous Source Current (Diode Conduction) <sup>1</sup>	$I_S$	1.5	A
Power Dissipation <sup>1</sup>	$P_D$	$T_A=25^\circ\text{C}$	1.2
		$T_A=70^\circ\text{C}$	0.8
Operating Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 ~ 150	$^\circ\text{C}$
<b>Thermal Resistance Rating</b>			
Maximum Junction to Ambient <sup>1</sup>	$R_{\theta JA}$	$t \leq 10$ sec	83
		Steady State	120
			$^\circ\text{C} / \text{W}$

Notes:

- 1 Surface Mounted on 1" x 1" FR4 Board.
- 2 Pulse width limited by maximum junction temperature.

**ELECTRICAL CHARACTERISTICS** ( $T_A = 25^\circ\text{C}$  unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Condition
<b>Static</b>						
Gate-Threshold Voltage	$V_{GS(th)}$	0.4	-	-	V	$V_{DS}=V_{GS}$ , $I_D=250\mu\text{A}$
Gate-Body Leakage	$I_{GSS}$	-	-	$\pm 100$	nA	$V_{DS}=0$ , $V_{GS}=\pm 12\text{V}$
Zero Gate Voltage Drain Current	$I_{DSS}$	-	-	1	uA	$V_{DS}=16\text{V}$ , $V_{GS}=0$
		-	-	10		$V_{DS}=16\text{V}$ , $V_{GS}=0$ , $T_J=55^\circ\text{C}$
On-State Drain Current <sup>1</sup>	$I_{D(on)}$	25	-	-	A	$V_{DS}=5\text{V}$ , $V_{GS}=4.5\text{V}$
Drain-Source On-Resistance <sup>1</sup>	$R_{DS(ON)}$	-	-	22	m $\Omega$	$V_{GS}=4.5\text{V}$ , $I_D=1\text{A}$
		-	-	30		$V_{GS}=2.5\text{V}$ , $I_D=1\text{A}$
		-	-	46		$V_{GS}=1.8\text{V}$ , $I_D=1\text{A}$
Forward Transconductance <sup>1</sup>	$g_{fs}$	-	25	-	S	$V_{DS}=10\text{V}$ , $I_D=1\text{A}$
Diode Forward Voltage	$V_{SD}$	-	0.7	-	V	$I_S=1\text{A}$ , $V_{GS}=0$
<b>Dynamic <sup>2</sup></b>						
Total Gate Charge	$Q_g$	-	6.2	-	nC	$V_{DS}=10\text{V}$ , $V_{GS}=4.5\text{V}$ , $I_D=1\text{A}$
Gate-Source Charge	$Q_{gs}$	-	1	-		
Gate-Drain Charge	$Q_{gd}$	-	1.9	-		
Turn-on Delay Time	$T_{d(on)}$	-	12	-	nS	$V_{DD}=10\text{V}$ , $V_{GS}=4.5\text{V}$ , $R_{GEN}=10\Omega$ , $I_D=1\text{A}$
Rise Time	$T_r$	-	15	-		
Turn-off Delay Time	$T_{d(off)}$	-	56	-		
Fall Time	$T_f$	-	17	-		

Notes:

- 1 Pulse test :  $PW \leq 300 \mu\text{s}$  duty cycle  $\leq 2\%$ .
- 2 Guaranteed by design, not subject to production testing.